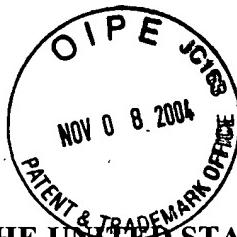


IRW



PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Rodney L. Kirstine

Serial No.: 10/642,921

Filed: August 18, 2003

For: METHOD AND APPARATUS FOR  
MEASUREMENT OF THICKNESS AND  
WARPAGE OF SUBSTRATES

Confirmation No.: 3659

Examiner: G. Yaritza

Group Art Unit: 2859

Attorney Docket No.: 2269-5659US  
02-1364.00/US

CERTIFICATE OF MAILING

I hereby certify that this correspondence along with any attachments referred to or identified as being attached or enclosed is being deposited with the United States Postal Service as First Class Mail on the date of deposit shown below with sufficient postage and in an envelope addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

November 5, 2004  
Date

*Rachael M. Harris*  
Signature

Rachael M. Harris  
Name (Type/Print)

AMENDMENT

Mail Stop Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

The following amendments and remarks are filed in response to the Examiner's remarks in the Office Action mailed August 12, 2004, the three-month shortened statutory period for response to which expires on November 12, 2004.

**Amendments to the Claims** are reflected in the listing of claims which begins on page 2 of this paper.

**Remarks/Arguments** begin on page 10 of this paper.